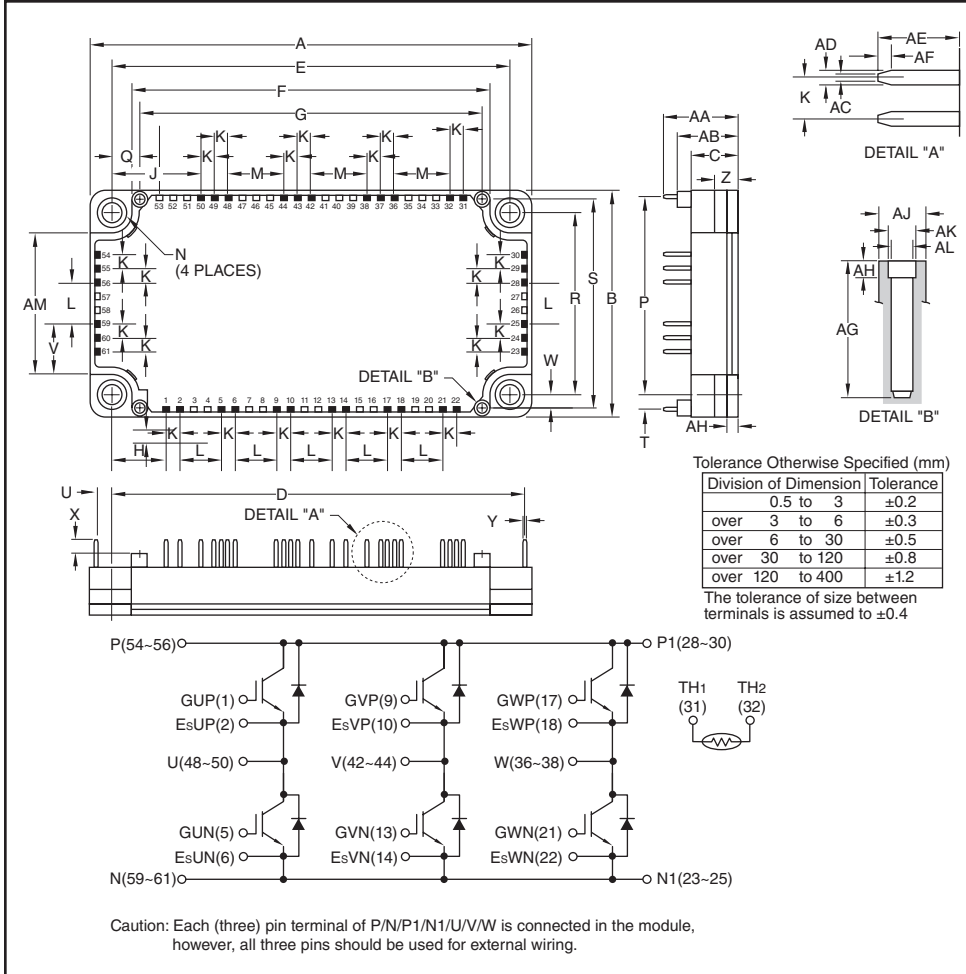


Six IGBT NX-Series Module 75 Amperes/1200 Volts



Outline Drawing and Circuit Diagram

Dimensions	Inches	Millimeters
A	4.79	121.7
B	2.44	62.0
C	0.51	13.0
D	4.49	114.05
E	4.33±0.02	110.0±0.5
F	3.9	99.0
G	3.72	94.5
H	0.59	15.0
J	0.96	24.52
K	0.15	3.81
L	0.45	11.43
M	0.6	15.24
N	0.22 Dia.	5.5 Dia.
P	2.13	54.2
Q	0.30	7.75
R	1.97±0.02	50.0±0.5
S	2.26	57.5
T	0.165	4.2

Dimensions	Inches	Millimeters
U	0.16	4.06
V	0.46	11.66
W	0.14	3.75
X	0.14	3.5
Y	0.03	0.8
Z	0.28	7.0
AA	0.81	20.5
AB	0.67	17.0
AC	0.03	0.65
AD	0.05	1.15
AE	0.29	7.4
AF	0.047	1.2
AG	0.49	12.5
AH	0.12	3.0
AJ	0.17 Dia.	4.3 Dia.
AK	0.102 Dia.	2.6 Dia.
AL	0.088 Dia.	2.25 Dia.
AM	1.53	39



Description:

Powerex IGBT Modules are designed for use in switching applications. Each module consists of six IGBT Transistors in a three phase bridge configuration with each transistor having a reverse-connected super-fast recovery free-wheel diode. All components and interconnects are isolated from the heat sinking baseplate, offering simplified system assembly and thermal management.

Features:

- ☐ Low Drive Power
- ☐ Low $V_{CE(sat)}$
- ☐ Discrete Super-Fast Recovery Free-Wheel Diode
- ☐ Isolated Baseplate for Easy Heat Sinking

Applications:

- ☐ AC Motor Control
- ☐ Motion/Servo Control
- ☐ Photovoltaic/Fuel Cell

Ordering Information:

Example: Select the complete module number you desire from the table below -i.e. CM75TX-24S is a 1200V (V_{CES}), 75 Ampere Six IGBT Power Module.

Type	Current Rating Amperes	V_{CES} Volts (x 50)
CM	75	24

CM75TX-24S
Six IGBT NX-Series Module
 75 Amperes/1200 Volts

Absolute Maximum Ratings, $T_j = 25^\circ\text{C}$ unless otherwise specified

Inverter Part IGBT/FWDi

Characteristics	Symbol	Rating	Units
Collector-Emitter Voltage ($V_{GE} = 0V$)	V_{CES}	1200	Volts
Gate-Emitter Voltage ($V_{CE} = 0V$)	V_{GES}	± 20	Volts
Collector Current (DC, $T_C = 122^\circ\text{C}$)*2,*4	I_C	75	Amperes
Collector Current (Pulse)*3	I_{CRM}	150	Amperes
Total Power Dissipation ($T_C = 25^\circ\text{C}$)*2,*4	P_{tot}	600	Watts
Emitter Current ($T_C = 25^\circ\text{C}$)*2	I_E^{*1}	75	Amperes
Emitter Current (Pulse)*3	I_{ERM}^{*1}	150	Amperes

Module

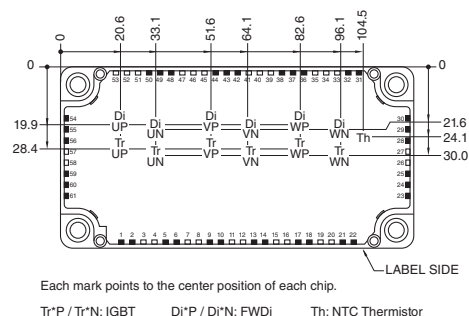
Characteristics	Symbol	Rating	Units
Isolation Voltage (Terminals to Baseplate, RMS, $f = 60\text{Hz}$, AC 1 minute)	V_{ISO}	2500	Volts
Maximum Junction Temperature, Instantaneous Event (Overload)	$T_{j(max)}$	175	$^\circ\text{C}$
Maximum Case Temperature*2	$T_{C(max)}$	125	$^\circ\text{C}$
Operating Junction Temperature, Continuous Operation (Under Switching)	$T_{j(op)}$	-40 to +150	$^\circ\text{C}$
Storage Temperature	T_{stg}	-40 to +125	$^\circ\text{C}$

*1 Represent ratings and characteristics of the anti-parallel, emitter-to-collector free wheeling diode (FWDi).

*2 Junction temperature (T_j) should not increase beyond maximum junction temperature ($T_{j(max)}$) rating.

*3 Pulse width and repetition rate should be such that device junction temperature (T_j) does not exceed $T_{j(max)}$ rating.

*4 Case temperature (T_C) and heatsink temperature (T_s) is measured on the surface (mounting side) of the baseplate and the heatsink side just under the chips. Refer to the figure to the right for chip location. The heatsink thermal resistance should be measured just under the chips.



CM75TX-24S
Six IGBT NX-Series Module
 75 Amperes/1200 Volts

Electrical Characteristics, $T_j = 25^\circ\text{C}$ unless otherwise specified

Inverter Part IGBT/FWDI

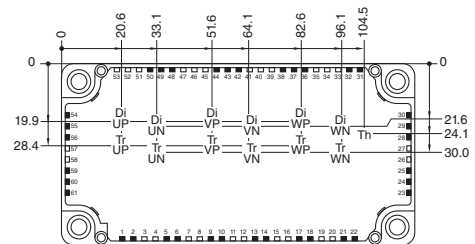
Characteristics	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Collector-Emitter Cutoff Current	I_{CES}	$V_{CE} = V_{CES}, V_{GE} = 0V$	—	—	1	mA
Gate-Emitter Leakage Current	I_{GES}	$V_{GE} = V_{GES}, V_{CE} = 0V$	—	—	0.5	μA
Gate-Emitter Threshold Voltage	$V_{GE(th)}$	$I_C = 7.5\text{mA}, V_{CE} = 10V$	5.4	6	6.6	Volts
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$ (Terminal)	$I_C = 75A, V_{GE} = 15V, T_j = 25^\circ\text{C}^{*5}$	—	1.80	2.25	Volts
		$I_C = 75A, V_{GE} = 15V, T_j = 125^\circ\text{C}^{*5}$	—	2.00	—	Volts
		$I_C = 75A, V_{GE} = 15V, T_j = 150^\circ\text{C}^{*5}$	—	2.05	—	Volts
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$ (Chip)	$I_C = 75A, V_{GE} = 15V, T_j = 25^\circ\text{C}^{*5}$	—	1.70	2.15	Volts
		$I_C = 75A, V_{GE} = 15V, T_j = 125^\circ\text{C}^{*5}$	—	1.90	—	Volts
		$I_C = 75A, V_{GE} = 15V, T_j = 150^\circ\text{C}^{*5}$	—	1.95	—	Volts
Input Capacitance	C_{ies}	$V_{CE} = 10V, V_{GE} = 0V$	—	—	7.5	nF
Output Capacitance	C_{oes}		—	—	1.5	nF
Reverse Transfer Capacitance	C_{res}		—	—	0.13	nF
Gate Charge	Q_G	$V_{CC} = 600V, I_C = 75A, V_{GE} = 15V$	—	175	—	nC
Turn-on Delay Time	$t_{d(on)}$	$V_{CC} = 600V, I_C = 75A, V_{GE} = \pm 15V,$ $R_G = 8.2\Omega$, Inductive Load	—	—	300	ns
Rise Time	t_r		—	—	200	ns
Turn-off Delay Time	$t_{d(off)}$		—	—	600	ns
Fall Time	t_f		—	—	300	ns
Emitter-Collector Voltage	V_{EC}^{*1} (Terminal)	$I_E = 75A, V_{GE} = 0V, T_j = 25^\circ\text{C}^{*5}$	—	1.80	2.25	Volts
		$I_E = 75A, V_{GE} = 0V, T_j = 125^\circ\text{C}^{*5}$	—	1.80	—	Volts
		$I_E = 75A, V_{GE} = 0V, T_j = 150^\circ\text{C}^{*5}$	—	1.80	—	Volts
Emitter-Collector Voltage	V_{EC}^{*1} (Chip)	$I_E = 75A, V_{GE} = 0V, T_j = 25^\circ\text{C}^{*5}$	—	1.70	2.15	Volts
		$I_E = 75A, V_{GE} = 0V, T_j = 125^\circ\text{C}^{*5}$	—	1.70	—	Volts
		$I_E = 75A, V_{GE} = 0V, T_j = 150^\circ\text{C}^{*5}$	—	1.70	—	Volts
Reverse Recovery Time	t_{rr}^{*1}	$V_{CC} = 600V, I_E = 75A, V_{GE} = \pm 15V$	—	—	300	ns
Reverse Recovery Charge	Q_{rr}^{*1}	$R_G = 8.2\Omega$, Inductive Load	—	4.0	—	μC
Turn-on Switching Energy per Pulse	E_{on}	$V_{CC} = 600V, I_C = I_E = 75A,$	—	7.3	—	mJ
Turn-off Switching Energy per Pulse	E_{off}	$V_{GE} = \pm 15V, R_G = 8.2\Omega,$	—	8.0	—	mJ
Reverse Recovery Energy per Pulse	E_{rr}^{*1}	$T_j = 150^\circ\text{C}$, Inductive Load	—	6.9	—	mJ
Internal Lead Resistance	$R_{CC'} + EE'$	Main Terminals-Chip, Per Switch, $T_C = 25^\circ\text{C}^{*4}$	—	—	2.4	m Ω
Internal Gate Resistance	r_g	Per Switch	—	0	—	Ω

*1 Represent ratings and characteristics of the anti-parallel, emitter-to-collector free wheeling diode (FWDI).

*4 Case temperature (T_C) and heatsink temperature (T_S) is measured on the surface (mounting side) of the baseplate and the heatsink side just under the chips. Refer to the figure to the right for chip location.

The heatsink thermal resistance should be measured just under the chips.

*5 Pulse width and repetition rate should be such as to cause negligible temperature rise.



Each mark points to the center position of each chip.

Tr*P / Tr*N: IGBT Di*P / Di*N: FWDI Th: NTC Thermistor

CM75TX-24S
Six IGBT NX-Series Module
75 Amperes/1200 Volts

Electrical Characteristics, T_j = 25°C unless otherwise specified (continued)

NTC Thermistor Part

Characteristics	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Zero Power Resistance	R ₂₅	T _C = 25°C*4	4.85	5.00	5.15	kΩ
Deviation of Resistance	ΔR/R	T _C = 100°C*4, R ₁₀₀ = 493Ω	-7.3	—	+7.8	%
B Constant	B _(25/50)	Approximate by Equation*6	—	3375	—	K
Power Dissipation	P ₂₅	T _C = 25°C*4	—	—	10	mW

Thermal Resistance Characteristics

Thermal Resistance, Junction to Case* ⁴	$R_{th(j-c)}Q$	Per Inverter IGBT	—	—	0.25	K/W
Thermal Resistance, Junction to Case* ⁴	$R_{th(j-c)}D$	Per Inverter FWD	—	—	0.40	K/W
Contact Thermal Resistance, Case to Heatsink* ⁴	$R_{th(c-f)}$	Thermal Grease Applied, Per 1 Module* ⁷	—	15	—	K/kW

Mechanical Characteristics

Mounting Torque	M _s	Mounting to Heatsink, M5 Screw	22	27	31	in-lb
Creepage Distance	d _s	Terminal to Terminal	10.28	—	—	mm
		Terminal to Baseplate	14.27	—	—	mm
Clearance	d _a	Terminal to Terminal	10.28	—	—	mm
		Terminal to Baseplate	12.33	—	—	mm
Weight	m		—	300	—	Grams
Flatness of Baseplate	e _c	On Centerline X, Y ^{*8}	±0	—	±100	μm

Recommended Operating Conditions, $T_a = 25^\circ\text{C}$

DC Supply Voltage	V _{CC}	Applied Across P-N Terminals	—	600	850	Volts
Gate-Emitter Drive Voltage	V _{GE(on)}	Applied Across G*P-Es*P/G*N-Es*N (* = U, V, W) Terminals	13.5	15.0	16.5	Volts
External Gate Resistance	R _G	Per Switch	8.2	—	82	Ω

*4 Case temperature (T_C) and heatsink temperature (T_S) is measured on the surface (mounting side) of the baseplate and the heatsink side just under the chips. Refer to the figure to the right for chip location. The heatsink thermal resistance should be measured just under the chips.

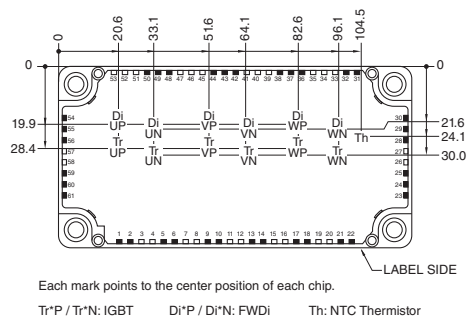
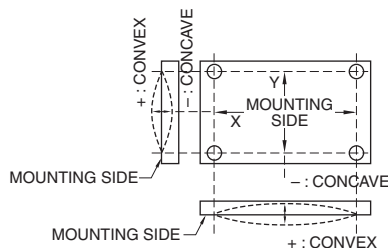
$$^*6 \ B_{(25/50)} = \ln\left(\frac{R_{25}}{B_{50}}\right) / \left(\frac{1}{T_{25}} - \frac{1}{T_{50}}\right)$$

R_{25} ; Resistance at Absolute Temperature T_{25} [K]; $T_{25} = 25$ [°C] + 273.15 = 298.15 [K]

R_{50} ; Resistance at Absolute Temperature T_{50} [K]; $T_{50} = 50$ [°C] + 273.15 = 323.15 [K]

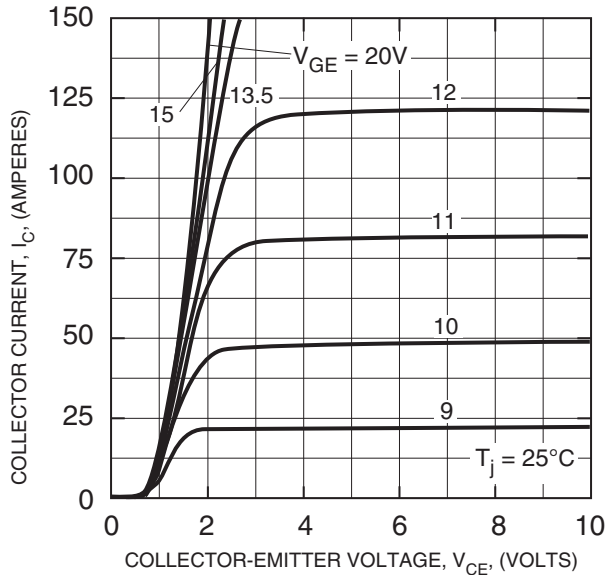
*7 Typical value is measured by using thermally conductive grease of $\lambda = 0.9$ [W/(m • K)].

*8 Baseplate (mounting side) flatness measurement points (X, Y) are shown in the figure below.

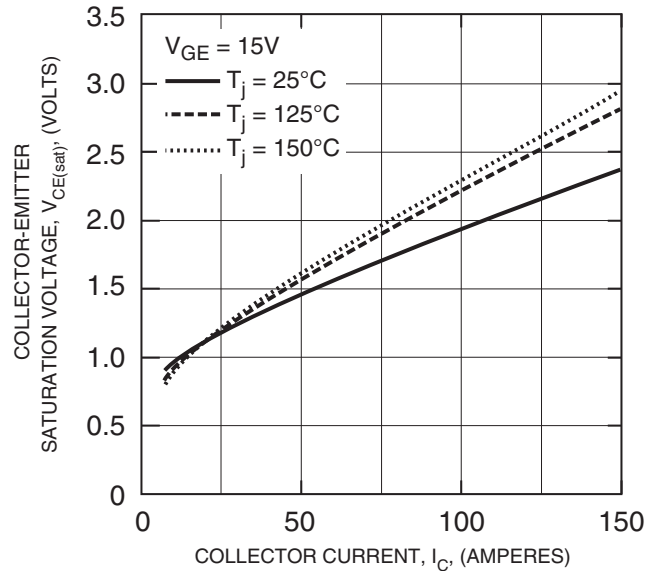


CM75TX-24S
Six IGBT NX-Series Module
 75 Amperes/1200 Volts

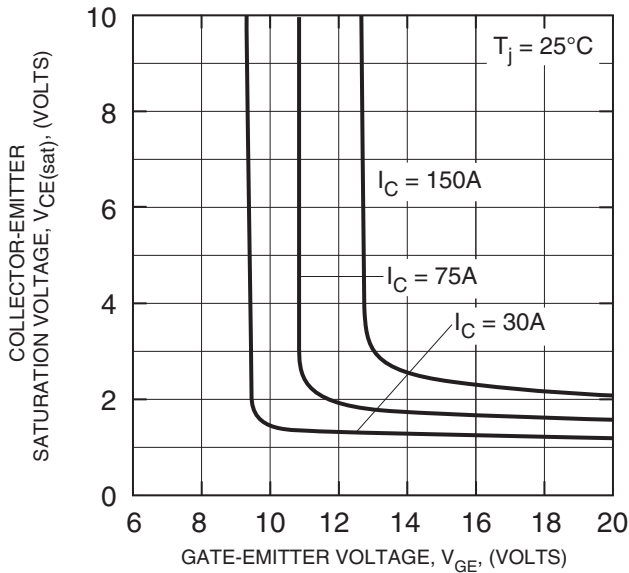
**OUTPUT CHARACTERISTICS
(TYPICAL)**



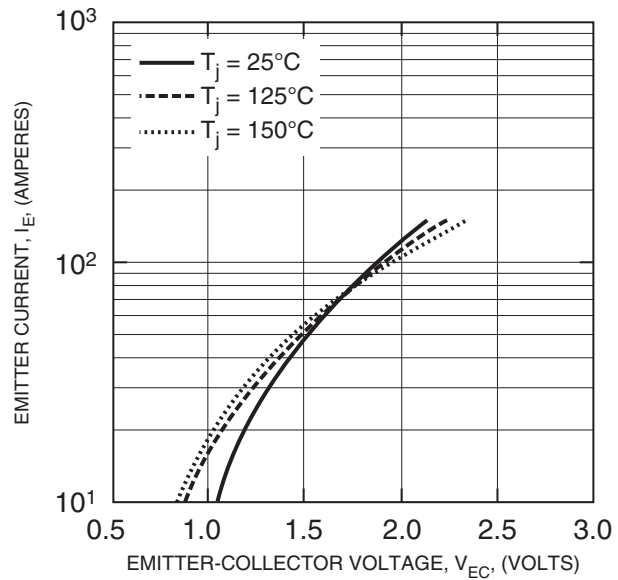
**COLLECTOR-EMITTER
SATURATION VOLTAGE CHARACTERISTICS
(TYPICAL)**



**COLLECTOR-EMITTER
SATURATION VOLTAGE CHARACTERISTICS
(TYPICAL)**

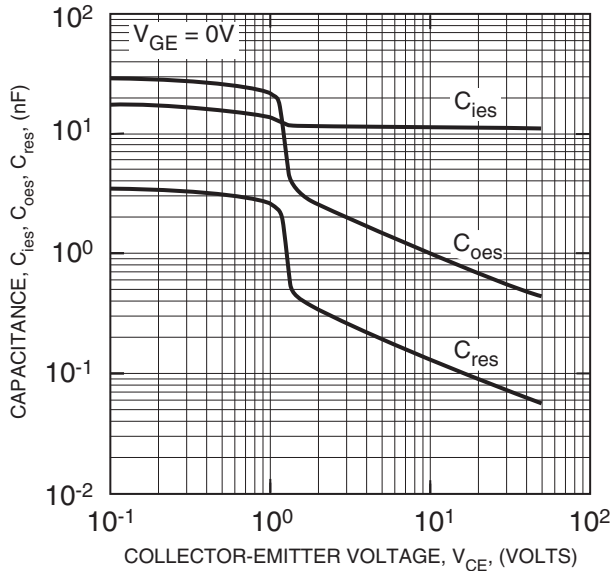


**FREE-WHEEL DIODE
FORWARD CHARACTERISTICS
(TYPICAL)**

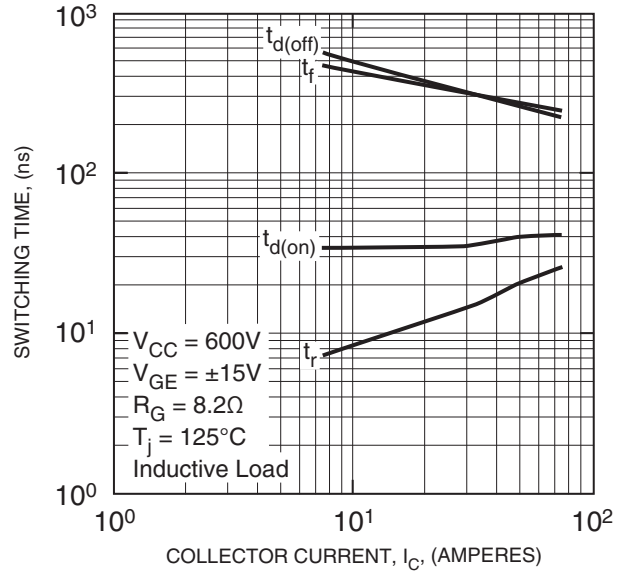


CM75TX-24S
Six IGBT NX-Series Module
 75 Amperes/1200 Volts

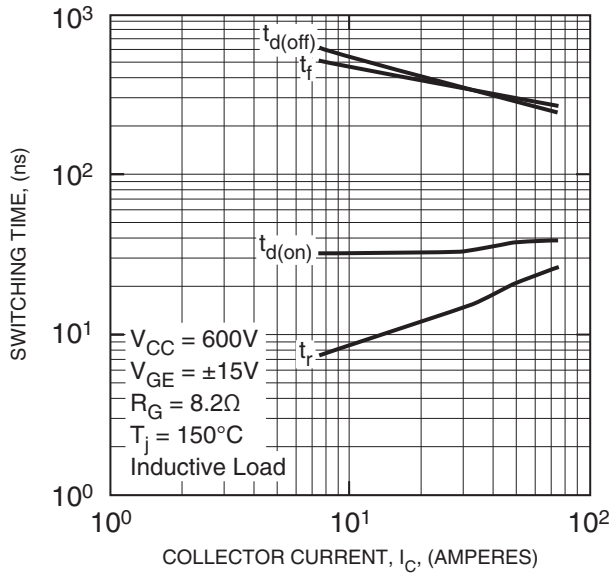
CAPACITANCE VS. V_{CE}
(TYPICAL)



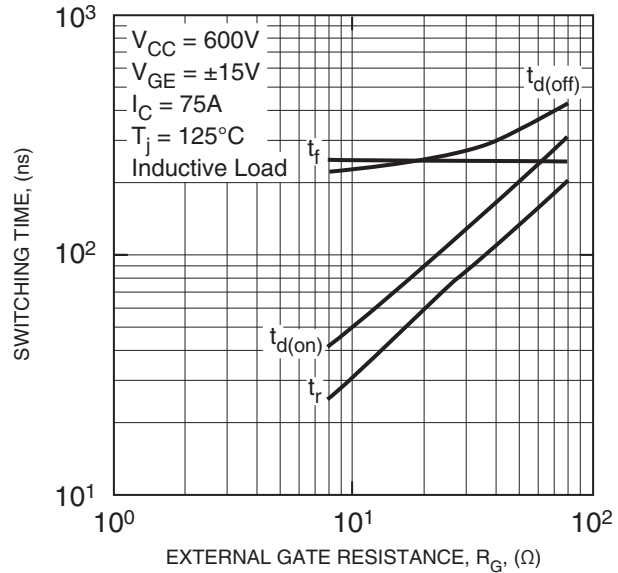
HALF-BRIDGE
SWITCHING CHARACTERISTICS
(TYPICAL)



HALF-BRIDGE
SWITCHING CHARACTERISTICS
(TYPICAL)

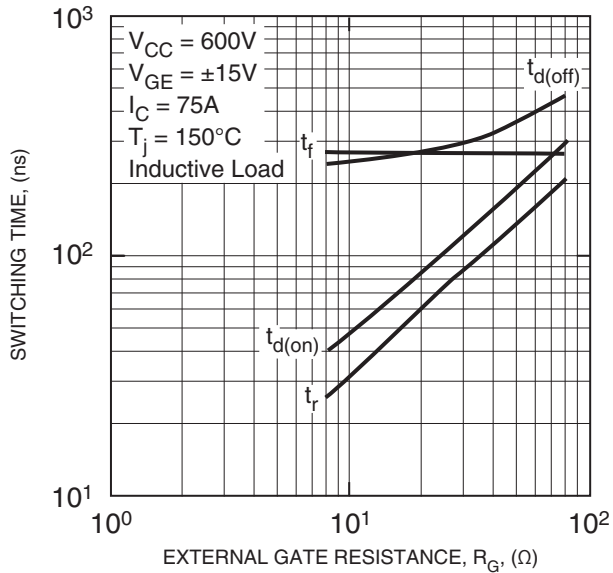


SWITCHING TIME VS.
GATE RESISTANCE
(TYPICAL)

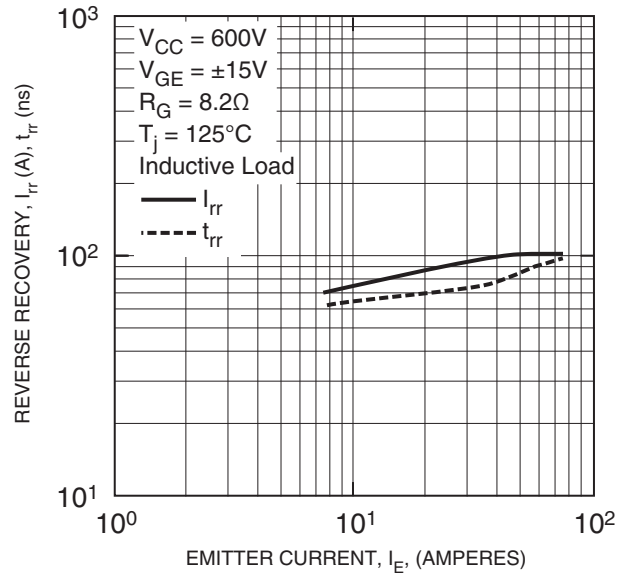


CM75TX-24S
Six IGBT NX-Series Module
 75 Amperes/1200 Volts

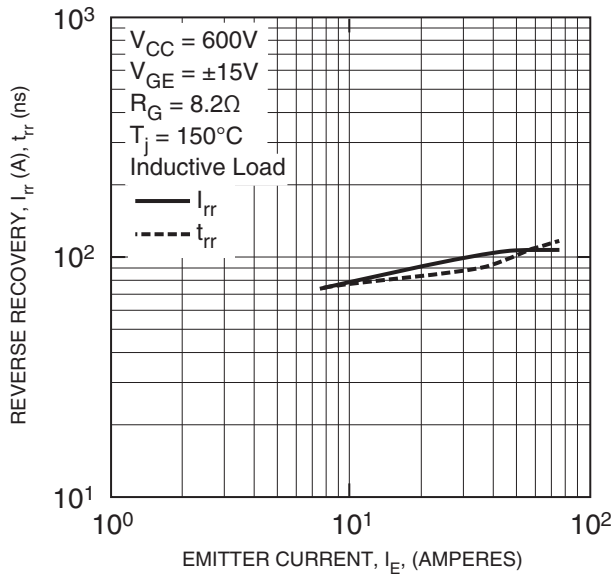
**SWITCHING TIME VS.
GATE RESISTANCE
(TYPICAL)**



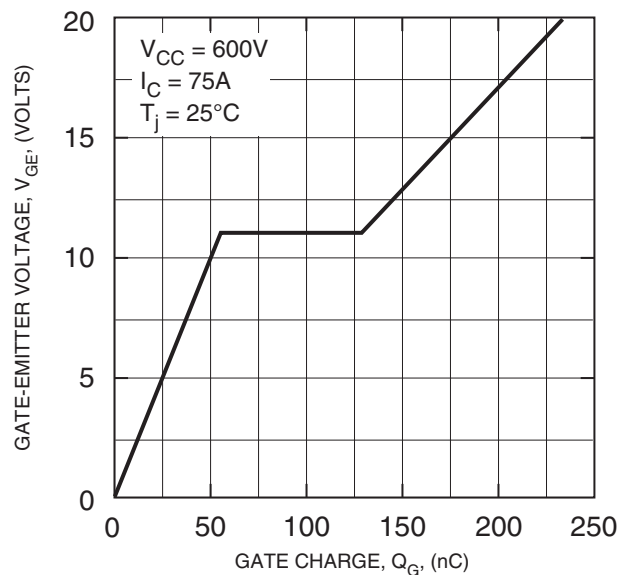
**REVERSE RECOVERY CHARACTERISTICS
(TYPICAL)**



**REVERSE RECOVERY CHARACTERISTICS
(TYPICAL)**

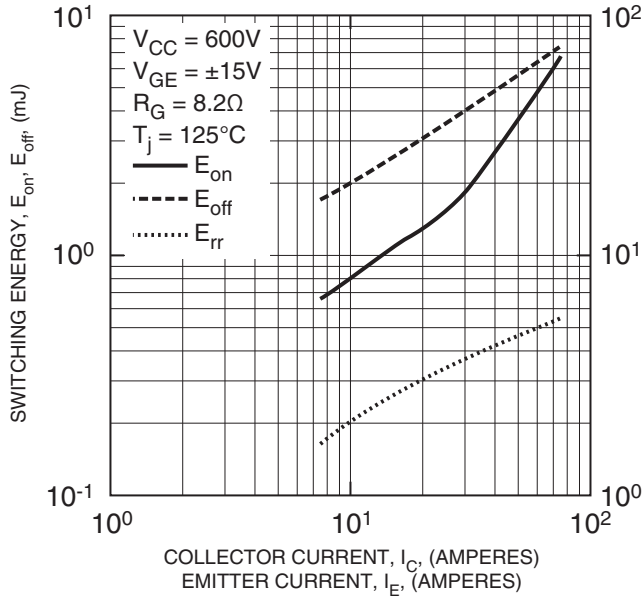


GATE CHARGE VS. V_{GE}

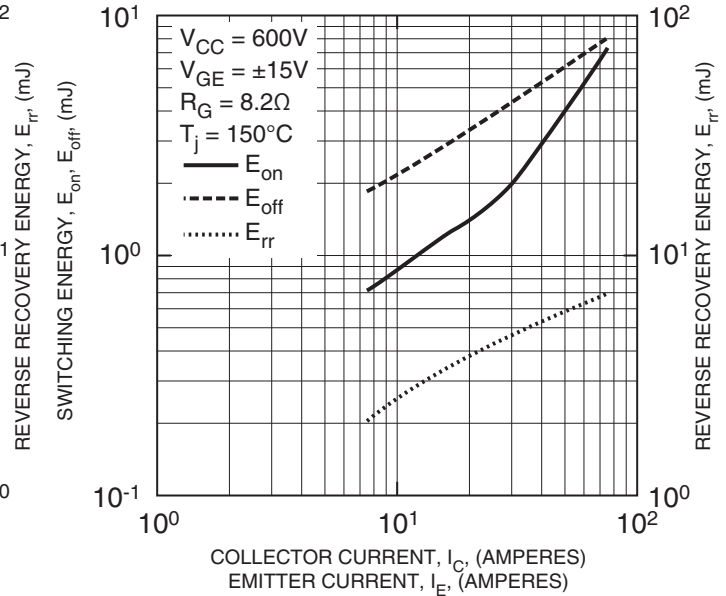


CM75TX-24S
Six IGBT NX-Series Module
 75 Amperes/1200 Volts

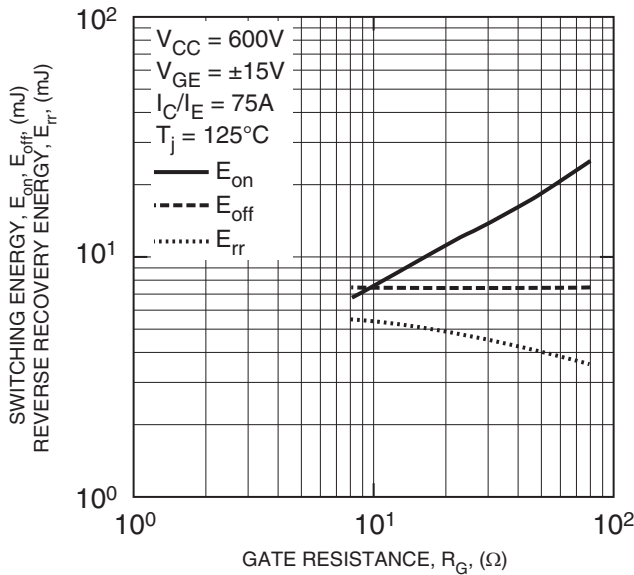
**HALF-BRIDGE SWITCHING
CHARACTERISTICS (TYPICAL)**



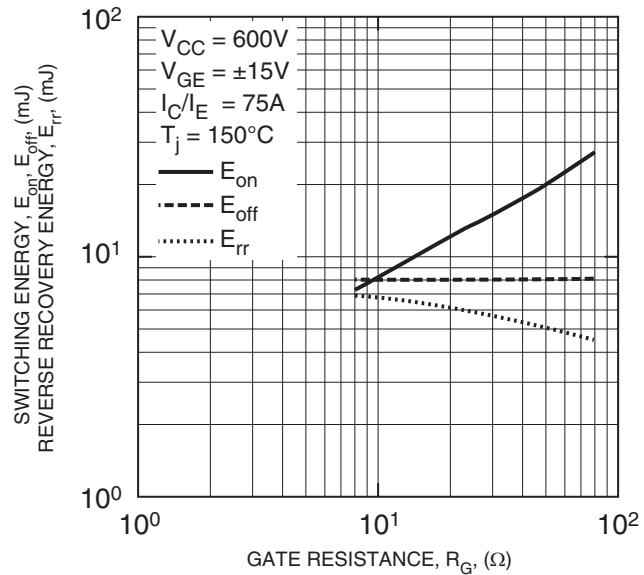
**HALF-BRIDGE SWITCHING
CHARACTERISTICS (TYPICAL)**



**HALF-BRIDGE SWITCHING
CHARACTERISTICS (TYPICAL)**



**HALF-BRIDGE SWITCHING
CHARACTERISTICS (TYPICAL)**



CM75TX-24S
Six IGBT NX-Series Module
75 Amperes/1200 Volts

